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(REV. 7-80) (Title Amended 3/83)			PATENT AND TRADEMARK OFFICE								RD-29,312		09/0	09/683,369		
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WD	AR	Kevin Harding & D. Svetkoff, "3D Laser Measurements On Scattering And Translucent Surfaces", SPIE Proceedings Vol. 2599, Three-dimensional and Unconventional Imaging for Industrial Inspection and Metrology, editor Harding, Phil. Oct. 1995, pp. 217-227,														
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